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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	150
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx24-3tq176

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2.4 Plastic Device Resources

Table 2 • Plastic Device Resources

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144- Pin	PQFP 160-Pin	PQFP 208- Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100- Pin	TQFP 176- Pin	PBGA 272- Pin
A40MX02	34	57	–	57	–	–	–	–	57	–	–	–
A40MX04	34	57	69	69	–	–	–	–	69	–	–	–
A42MX09	–	–	72	83	95	101	–	–	–	83	104	–
A42MX16	–	–	72	83	–	125	140	–	–	83	140	–
A42MX24	–	–	72	–	–	125	176	–	–	–	150	–
A42MX36	–	–	–	–	–	–	176	202	–	–	–	202

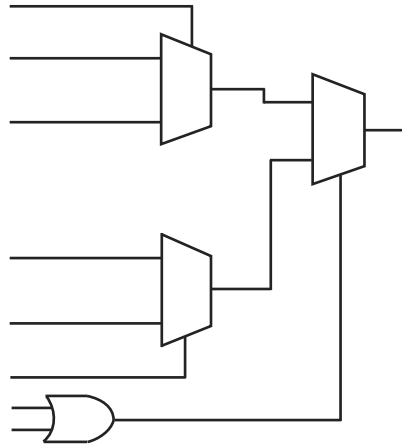
Note: Package Definitions: PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

2.5 Ceramic Device Resources

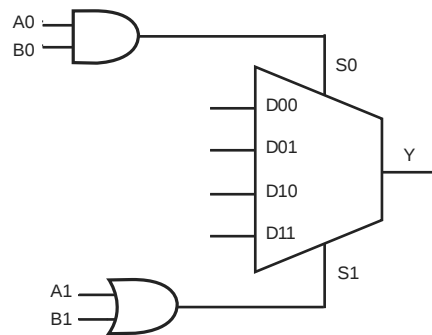
Table 3 • Ceramic Device Resources

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

Note: Package Definitions: CQFP = Ceramic Quad Flat Pack

Figure 2 • 42MX C-Module Implementation

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

Figure 3 • 42MX C-Module Implementation

3. All outputs unloaded. All inputs = VCC/VCCI or GND

3.8 3.3 V Operating Conditions

The following table shows 3.3 V operating conditions.

Table 16 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCC + 0.5	V
VO	Output Voltage	–0.5 to VCC + 0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 17 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCI+0.5	V
VO	Output Voltage	–0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 18 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCC (40MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCA (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCI (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

All the following tables show various specifications and operating conditions of 40MX and 42MX FPGAs.

3.9.1 Mixed 5.0V/3.3V Electrical Specifications

Table 22 • Mixed 5.0V/3.3V Electrical Specifications

Symbol	Parameter	Commercial		Commercial –F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					2.4		2.4		V
VOL ¹	IOL = 10 mA	0.5		0.5						V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V	–10		–10		–10		–10		μA
IH	VIN = 2.7 V	–10		–10		–10		–10		μA
Input Transition Time, TR and TF		500		500		500		500		ns
C _{IO} I/O Capacitance		10		10		10		10		pF
Standby Current, ICC ³	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	20		25		25		25		mA
Low Power Mode Standby Current		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0		mA
I/O I/O source sink current Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)										

1. Only one output tested at a time. VCCI = min.

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

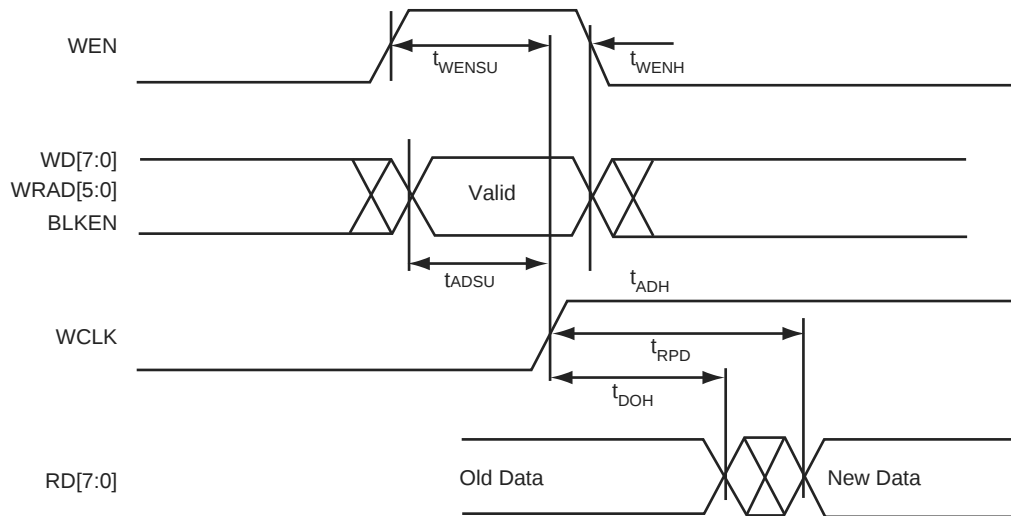
3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • DC Specification (5.0 V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		–0.5	0.8	–0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70	—	10	μA
IIL	Input Low Leakage Current	VIN=0.5 V		–70	—	–10	μA
VOH	Output High Voltage	IOUT = –2 mA IOUT = –6 mA	2.4		3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.55	—	0.33	V

Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 μm lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

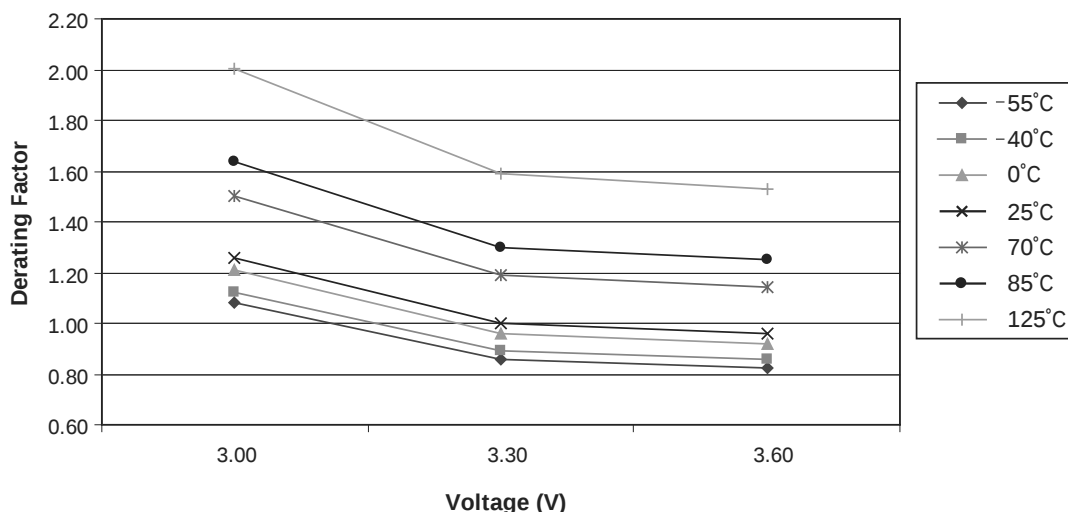
Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add

Table 31 • 40MX Temperature and Voltage Derating Factors (Normalized to T_J = 25°C, V_{CC} = 3.3 V)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.60	0.83	0.85	0.92	0.96	1.14	1.25	1.53

Figure 37 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to T_J = 25°C, V_{CC} = 3.3 V)

Note: This derating factor applies to all routing and propagation delays

3.11.5 PCI System Timing Specification

The following tables list the critical PCI timing parameters and the corresponding timing parameters for the MX PCI-compliant devices.

3.11.6 PCI Models

Microsemi provides synthesizable VHDL and Verilog-HDL models for a PCI Target interface, a PCI Target and Target+DMA Master interface. Contact the Microsemi sales representative for more details.

Table 32 • Clock Specification for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{CYC}	CLK Cycle Time	30	–	4.0	–	4.0	–	ns
t _{HIGH}	CLK High Time	11	–	1.9	–	1.9	–	ns
t _{LOW}	CLK Low Time	11	–	1.9	–	1.9	–	ns

Table 33 • Timing Parameters for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{VAL}	CLK to Signal Valid—Bused Signals	2	11	2.0	9.0	2.0	9.0	ns
t _{VAL(PTP)}	CLK to Signal Valid—Point-to-Point	2 ²	12	2.0	9.0	2.0	9.0	ns
t _{ON}	Float to Active	2	–	2.0	4.0	2.0	4.0	ns
t _{OFF}	Active to Float	–	28	–	8.3 ¹	–	8.3 ¹	ns
t _{SU}	Input Set-Up Time to CLK—Bused Signals	7	–	1.5	–	1.5	–	ns

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5		ns
t _{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3		ns
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.1		2.4		2.2		3.2		4.5		ns
t _{IRD2}	FO = 2 Routing Delay		2.6		3.0		3.4		4.0		5.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.1		3.6		4.1		4.8		6.7		ns
t _{IRD4}	FO = 4 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD8}	FO = 8 Routing Delay		5.7		6.6		7.5		8.8		12.4		ns
Global Clock Network													
t _{CKH}	Input Low to HIGH	FO = 16 FO = 128	4.6 4.6		5.3 5.3		6.0 6.0		7.0 7.0		9.8 9.8		ns
t _{CKL}	Input High to LOW	FO = 16 FO = 128	4.8 4.8		5.6 5.6		6.3 6.3		7.4 7.4		10.4 10.4		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.1		3.4 3.6		4.8 5.1		ns	
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.01		3.4 3.6		4.8 5.1		ns	
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.4 0.5		0.5 0.6		0.5 0.7		0.6 0.8		0.8 1.2		ns
t _P	Minimum Period	FO = 16 FO = 128	4.7 4.8	5.4 5.6		6.1 6.3		7.2 7.5		10.0 10.4		ns	
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	188 181		175 168		160 154		139 134		83 80		MHz

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.9		3.3		3.8		4.5		6.3		ns
t _{IRD2}	FO = 2 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD3}	FO = 3 Routing Delay		4.4		5.0		5.7		6.7		9.4		ns
t _{IRD4}	FO = 4 Routing Delay		5.1		5.9		6.7		7.8		11.0		ns
t _{IRD8}	FO = 8 Routing Delay		8.0		9.3		10.5		12.4		17.2		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 16 FO = 128	6.4 6.4		7.4 7.4		8.4 8.4		9.9 9.9		13.8 13.8		ns
t _{CKL}	Input HIGH to LOW	FO = 16 FO = 128	6.8 6.8		7.8 7.8		8.9 8.9		10.4 10.4		14.6 14.6		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.6 0.8		0.6 0.9		0.7 1.0		0.8 1.2		1.2 1.6		ns
t _P	Minimum Period	FO = 16 FO = 128	6.5 6.8		7.5 7.8		8.5 8.9		10.1 10.4		14.1 14.6		ns
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	113 109		105 101		96 92		83 80		50 48		MHz
TTL Output Module Timing ⁴													
t _{DLH}	Data-to-Pad HIGH		4.7		5.4		6.1		7.2		10.0		ns
t _{DHL}	Data-to-Pad LOW		5.6		6.4		7.3		8.6		12.0		ns
t _{ENZH}	Enable Pad Z to HIGH		5.2		6.0		6.9		8.1		11.3		ns
t _{ENZL}	Enable Pad Z to LOW		6.6		7.6		8.6		10.1		14.1		ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9		ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7		ns
d _{TLH}	Delta LOW to HIGH		0.03		0.03		0.04		0.04		0.06		ns/pF
d _{THL}	Delta HIGH to LOW		0.04		0.04		0.05		0.06		0.08		ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Asynchronous SRAM Operations													
t _{RPD}	Asynchronous Access Time		8.1		9.0		10.2		12.0		16.8		ns
t _{RDADV}	Read Address Valid		8.8		9.8		11.1		13.0		18.2		ns
t _{ADSU}	Address/Data Set-Up Time		1.6		1.8		2.0		2.4		3.4		ns
t _{ADH}	Address/Data Hold Time		0.0		0.0		0.0		0.0		0.0		ns
t _{RENSUA}	Read Enable Set-Up to Address Valid		0.6		0.7		0.8		0.9		1.3		ns
t _{RENHA}	Read Enable Hold		3.4		3.8		4.3		5.0		7.0		ns
t _{WENSU}	Write Enable Set-Up		2.7		3.0		3.4		4.0		5.6		ns
t _{WENH}	Write Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{DOH}	Data Out Hold Time		1.2		1.3		1.5		1.8		2.5		ns
Input Module Propagation Delays													
t _{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1		ns
t _{INGO}	Input Latch Gate-to-Output		1.4		1.6		1.8		2.1		2.9		ns
t _{INH}	Input Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up		0.5		0.5		0.6		0.7		1.0		ns
t _{ILA}	Latch Active Pulse Width		4.7		5.2		5.9		6.9		9.7		ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.0		2.2		2.5		2.9		4.1		ns
t _{IRD2}	FO = 2 Routing Delay		2.3		2.6		2.9		3.4		4.8		ns
t _{IRD3}	FO = 3 Routing Delay		2.6		2.9		3.3		3.9		5.5		ns
t _{IRD4}	FO = 4 Routing Delay		3.0		3.3		3.8		4.4		6.2		ns
t _{IRD8}	FO = 8 Routing Delay		4.3		4.8		5.5		6.4		9.0		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	2.7	3.0	3.4	4.0	5.6	ns					
		FO = 635	3.0	3.3	3.8	4.4	6.2	ns					
t _{CKL}	Input HIGH to LOW	FO = 32	3.8	4.2	4.8	5.6	7.8	ns					
		FO = 635	4.9	5.4	6.1	7.2	10.1	ns					
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.8	2.0	2.2	2.6	3.6	ns					
		FO = 635	2.0	2.2	2.5	2.9	4.1	ns					
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.8	2.0	2.2	2.6	3.6	ns					
		FO = 635	2.0	2.2	2.5	2.9	4.1	ns					
t _{CKSW}	Maximum Skew	FO = 32	0.8	0.8	0.9	1.0	1.4	ns					
		FO = 635	0.8	0.8	0.9	1.0	1.4	ns					

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCC	VCC
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	GND	GND
50	I/O	I/O
51	I/O	I/O
52	CLK, I/O	CLK, I/O
53	I/O	I/O
54	MODE	MODE
55	VCC	VCC
56	SDI, I/O	SDI, I/O
57	DCLK, I/O	DCLK, I/O
58	PRA, I/O	PRA, I/O
59	PRB, I/O	PRB, I/O
60	I/O	I/O

Figure 42 • PQ144

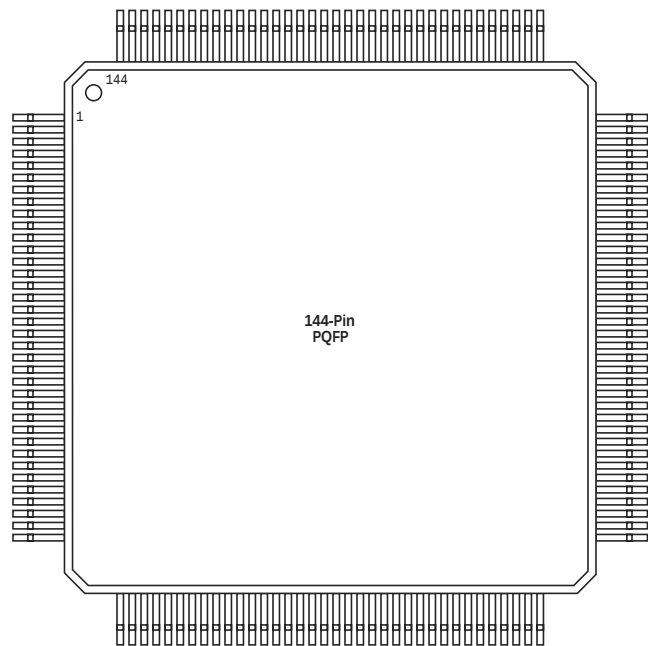


Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
58	I/O	WD, I/O	WD, I/O
59	I/O	I/O	I/O
60	VCCI	VCCI	VCCI
61	NC	I/O	I/O
62	NC	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	QCLKA, I/O
66	I/O	WD, I/O	WD, I/O
67	NC	WD, I/O	WD, I/O
68	NC	I/O	I/O
69	I/O	I/O	I/O
70	I/O	WD, I/O	WD, I/O
71	I/O	WD, I/O	WD, I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	GND	GND	GND
79	VCCA	VCCA	VCCA
80	NC	VCCI	VCCI
81	I/O	I/O	I/O
82	I/O	I/O	I/O
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	WD, I/O	WD, I/O
86	I/O	WD, I/O	WD, I/O
87	I/O	I/O	I/O
88	I/O	I/O	I/O
89	NC	I/O	I/O
90	NC	I/O	I/O
91	I/O	I/O	QCLKB, I/O
92	I/O	I/O	I/O
93	I/O	WD, I/O	WD, I/O
94	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	NC	VCCA	VCCA
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	GND	GND	GND
19	NC	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	NC	I/O	I/O
23	GND	GND	GND
24	NC	VCCI	VCCI
25	VCCA	VCCA	VCCA
26	NC	I/O	I/O
27	NC	I/O	I/O
28	VCCI	VCCA	VCCA
29	NC	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	NC	NC	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	NC	I/O	I/O
38	NC	NC	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	GND	GND	GND
46	I/O	I/O	TMS, I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
148	I/O
149	I/O
150	GND
151	I/O
152	I/O
153	I/O
154	I/O
155	I/O
156	I/O
157	GND
158	I/O
159	SDI, I/O
160	I/O
161	WD, I/O
162	WD, I/O
163	I/O
164	VCCI
165	I/O
166	I/O
167	I/O
168	WD, I/O
169	WD, I/O
170	I/O
171	QCLKD, I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	WD, I/O
177	WD, I/O
178	PRA, I/O
179	I/O
180	CLKA, I/O
181	I/O
182	VCCI
183	VCCA
184	GND

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
244	WD, I/O
245	I/O
246	I/O
247	I/O
248	VCCI
249	I/O
250	WD, I/O
251	WD, I/O
252	I/O
253	SDI, I/O
254	I/O
255	GND
256	NC

Figure 51 • BG272

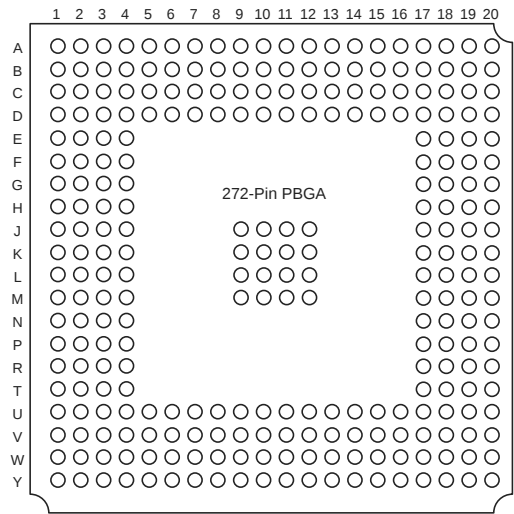


Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
A1	GND
A2	GND
A3	I/O
A4	WD, I/O
A5	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND

Table 62 • CQ172

138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK